



# Accredited Laboratory

A2LA has accredited

**THERMOWORKS, INC.**

*American Fork, UT*

for technical competence in the field of

**Calibration**

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017 *General requirements for the competence of testing and calibration laboratories*. This laboratory also meets the requirements of ANSI/NCSL Z540-1-1994 and R205 – Specific Requirements: Calibration Laboratory Accreditation Program. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

Presented this 22<sup>nd</sup> day of August 2024.

A blue ink signature of Mr. Trace McInturff, Vice President of Accreditation Services.

Mr. Trace McInturff, Vice President, Accreditation Services  
For the Accreditation Council  
Certificate Number 4024.01  
Valid to May 31, 2026



*For the calibrations to which this accreditation applies, please refer to the laboratory's Calibration Scope of Accreditation.*



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017  
& ANSI/NCSL Z540-1-1994

THERMOWORKS, INC.  
 741 East Utah Valley Drive  
 American Fork, UT 84003  
 Thomas Wiandt Phone: 801 756 7705

CALIBRATION

Valid To: May 31, 2026

Certificate Number: 4024.01

In recognition of the successful completion of the A2LA evaluation process (including an assessment of the organization's compliance with A2LA's Calibration Program Requirements), accreditation is granted to this laboratory to perform the following calibrations<sup>1,5</sup>:

I. Electrical – DC/Low Frequency

Parameter/Equipment	Range	CMC <sup>2,6</sup> (±)	Comments
DC Voltage – Generate and Measure	± (0 to 100) mV ± (> 0.1 to 1.0) V ± (> 1.0 to 10.0) V ± (> 10.0 to 100) V ± (> 100 to 1000) V	9.0 μV/V + 2.5 μV 5.0 μV/V + 0.4 μV 5.0 μV/V + 1.0 μV 8.0 μV/V + 40 μV 8.0 μV/V + 0.65 mV	Fluke 8588A DMM, Various voltage sources
DC Current – Generate	± (0 to 100) mA	57 μA/A + 1.3 μA	Fluke 7526A
DC Current – Measure and Enhanced Generate	± (0 to 100) mA	10 μA/A + 0.25 μA	Fluke 8588A DMM, Fluke 7526A Process Calibrator, Shunt
DC Resistance – Generate	(10 to 1111.11) Ω (> 1.1 to 4.0) kΩ	60 μΩ/Ω 0.35 Ω	IET RTD-Z-.001 Fluke 7526A
DC Resistance – Measure Transfer	(10 to 40) Ω (> 40 to 200) Ω (> 200 to 400) Ω	3 μΩ/Ω + 70 μΩ 3 μΩ/Ω + 0.5 mΩ 1 μΩ/Ω + 1.5 mΩ	Fluke 8588A DMM Measurements International 9331 Reference Resistors

Parameter/Equipment	Range	CMC <sup>2, 6</sup> (±)	Comments
DC Resistance – Measure Bridge Measurement	(0 to 1.2) Ω (0 to 12) Ω (0 to 120) Ω (0 to 400) Ω (0 to 10) kΩ (10 to 40) kΩ (40 to 100) kΩ (100 to 500) kΩ	Greater of 14 μΩ or 48 μΩ/Ω Greater of 28 μΩ or 12 μΩ/Ω Greater of 40 μΩ or 6 μΩ/Ω Greater of 95 μΩ or 5 μΩ/Ω Greater of 140 μΩ or 6 μΩ/Ω 10 μΩ/Ω 25 μΩ/Ω 95 μΩ/Ω	Fluke 1595A resistance bridge
DC Resistance – Measure Direct Measurement	(0 to 2.0) Ω (> 2 to 20) Ω (> 20 to 200) Ω (> 0.2 to 2.0) kΩ (> 2.0 to 20) kΩ (> 20 to 200) kΩ (> 0.2 to 2.0) MΩ	20 μΩ/Ω + 7.5 μΩ 12 μΩ/Ω + 20 μΩ 12 μΩ/Ω + 100 μΩ 12 μΩ/Ω + 1.0 mΩ 12 μΩ/Ω + 10 mΩ 12 μΩ/Ω + 0.1 Ω 13 μΩ/Ω + 1.0 Ω	Fluke 8588A DMM
Electrical Calibration of Thermocouple Indicating Devices – Measure and Generate			
Type E	(-270 to < -245) °C (-245 to < -195) °C (-195 to < -155) °C (-155 to < -90) °C (-90 to < 15) °C (15 to < 890) °C (890 to 1000) °C	1.5 °C 0.24 °C 0.12 °C 0.10 °C 0.09 °C 0.07 °C 0.08 °C	Fluke 7526A
Type J	(-210 to < -180) °C (-180 to < -120) °C (-120 to < -50) °C (-50 to 1200) °C	0.15 °C 0.12 °C 0.10 °C 0.09 °C	
Type K	(-270 to < -255) °C (-255 to < -195) °C (-195 to < -115) °C (-115 to < -55) °C (-55 to < 1000) °C (1000 to 1372) °C	2.8 °C 0.85 °C 0.15 °C 0.11 °C 0.09 °C 0.10 °C	

Parameter/Equipment	Range	CMC <sup>2,6</sup> (±)	Comments
Electrical Calibration of Thermocouple Indicating Devices – Measure and Generate (cont)			
Type N	(-270 to < -260) °C (-260 to < -200) °C (-200 to < -145) °C (-145 to < -70) °C (-70 to < 25) °C (25 to < 160) °C (160 to 1300) °C	5.8 °C 1.3 °C 0.28 °C 0.18 °C 0.14 °C 0.12 °C 0.11 °C	Fluke 7526A
Type R	(-50 to < -30) °C (-30 to < 45) °C (45 to < 160) °C (160 to < 380) °C (380 to < 775) °C (775 to 1768) °C	0.78 °C 0.66 °C 0.48 °C 0.36 °C 0.31 °C 0.22 °C	
Type S	(-50 to < -30) °C (-30 to < 45) °C (45 to < 105) °C (105 to < 310) °C (310 to < 615) °C (615 to 1768) °C	0.74 °C 0.67 °C 0.48 °C 0.40 °C 0.35 °C 0.31 °C	
Type T	(-270 to < -255) °C (-255 to < -240) °C (-240 to < -210) °C (-210 to < -150) °C (-150 to < -40) °C (-40 to < 100) °C (100 to 400) °C	2.3 °C 0.59 °C 0.36 °C 0.22 °C 0.14 °C 0.10 °C 0.09 °C	

Parameter/Equipment	Range	CMC <sup>2, 3, 6</sup> (±)	Comments
Electrical Calibration of Thermocouple Reference Junctions – Measure and Generate			
Type E, J, K, N, T	0 °C (21 to 25) °C	0.06 °C 0.06 °C	Characterized thermocouple or thermocouple reference junction probe (RJP)
Type R, S	0 °C (21 to 25) °C	0.085 °C 0.085 °C	
Electrical Calibration of RTD Indicating Devices – Generate			
Pt 100	(-200 to 500) °C (> 500 to 800) °C	(0.006 % + 0.020) °C (0.007 % + 0.018) °C	IET RTD-Z-6-.001
Pt 200	(-200 to 800) °C (> 500 to 800) °C	(0.006 % + 0.020) °C (0.007 % + 0.018) °C	IET RTD-Z-6-.001
Pt 500	(-200 to 325) °C (> 325 to 800) °C	(0.006 % + 0.016) °C (0.011 % + 0.19) °C	IET RTD-Z-6-.001 Fluke 7526A
Pt 1000	(-200 to 800) °C	(0.0045 % + 0.10) °C	Fluke 7526A

II. Thermodynamics

Parameter/Equipment	Range	CMC <sup>2,4</sup> (±)	Comments
Temperature – Measure	(-200 to < -80) °C (-80 to < 0) °C 0 °C (> 0 to 100) °C (> 100 to 200) °C (> 200 to 300) °C (> 300 to 420) °C	0.0050 °C 0.0060 °C 0.0050 °C 0.0060 °C 0.0075 °C 0.010 °C 0.012 °C	Fluke 1595A with SPRT/TPW cell
	(-200 to < -80) °C (-80 to < 0) °C 0 °C (> 0 to 100) °C (> 100 to 200) °C (> 200 to 300) °C (> 300 to 400) °C (> 400 to 500) °C (> 500 to 600) °C (> 600 to 660) °C	0.009 °C 0.008 °C 0.007 °C 0.009 °C 0.011 °C 0.014 °C 0.016 °C 0.018 °C 0.020 °C 0.023 °C	Fluke 1595A with PRT
Temperature – Measuring Equipment	(-80 to < 0) °C 0 °C (> 0 to 100) °C (> 100 to 200) °C (> 200 to 300) °C (> 300 to 420) °C	0.0060 °C 0.0050 °C 0.0060 °C 0.0080 °C 0.010 °C 0.012 °C	Fluke 1595A with SPRT/TPWcell/bath
	(-80 to < 0) °C 0 °C (> 0 to 100) °C (> 100 to 200) °C (> 200 to 300) °C (> 300 to 400) °C (> 400 to 500) °C (> 500 to 600) °C (> 600 to 660) °C	0.008 °C 0.007 °C 0.009 °C 0.012 °C 0.014 °C 0.016 °C 0.018 °C 0.022 °C 0.025 °C	Fluke 1595A with PRT/baths/dry-block calibrators
Non-Contact (IR) Thermometry – Measuring Equipment	(-15 to 0) °C 35 °C 100 °C 200 °C 350 °C 500 °C (> 500 to 700) °C	0.60 °C 0.55 °C 0.70 °C 1.0 °C 1.6 °C 2.1 °C 2.5 °C	Fluke 4180, Fluke 4181, Isotech R700

Parameter/Equipment	Range	CMC <sup>2,4</sup> (±)	Comments
Relative Humidity – Measuring Equipment	(10 to 50) % RH (> 50 to 75) % RH (> 75 to 90) % RH  (15 to 20) °C (> 20 to 25) °C (> 25 to 35) °C	0.55 % RH 0.60 % RH 0.65 % RH  0.060 °C 0.055 °C 0.060 °C	Thunder Scientific 2500 humidity generator

<sup>1</sup> This laboratory offers commercial calibration service.

<sup>2</sup> Calibration and Measurement Capability Uncertainty (CMC) is the smallest uncertainty of measurement that a laboratory can achieve within its scope of accreditation when performing more or less routine calibrations of nearly ideal measurement standards or nearly ideal measuring equipment. CMCs represent expanded uncertainties expressed at approximately the 95 % level of confidence, usually using a coverage factor of  $k = 2$ . The actual measurement uncertainty of a specific calibration performed by the laboratory may be greater than the CMC due to the behavior of the customer's device and to influences from the circumstances of the specific calibration.

<sup>3</sup> In the statement of CMC, percentages are percentage of reading, unless otherwise indicated.

<sup>4</sup> The type of instrument or material being calibrated is defined by the parameter. This indicates the laboratory is capable of calibrating instruments that measure or generate the values in the ranges indicated for the listed measurement parameter.

<sup>5</sup> This scope meets A2LA's *P112 Flexible Scope Policy*.

<sup>6</sup> The stated measured values are determined using the indicated instrument (see Comments). This capability is suitable for the calibration of the devices intended to measure or generate the measured value in the ranges indicated.